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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/614,215	LEE ET AL.	
Examiner	Art Unit	
Dieu-Minh Le	2114	

SEARCHED				
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Class	Subclass '	Date	Examiner	
714	49	9/16/2006	DML	
	51			
	12			
712	218	9/16/2006	DML	
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
714	49	9/16/2006	DML	
712	218	9/16/2006	DML	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST search files USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM-TDB.	9/16/2006	DMĽ
Inventor name search.	9/16/2006	DML
NPL search [IEEE & ACM]	9/16/2006	DML
Interference search - see text search print out.	9/16/2006	DML
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